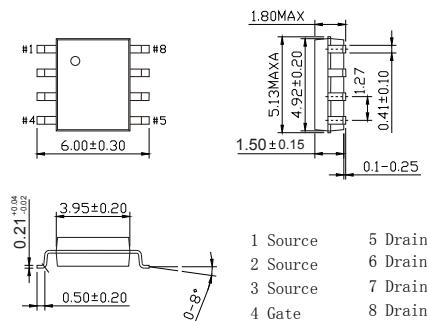
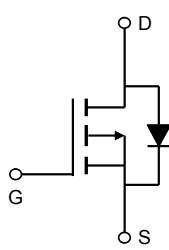


## ■ Features

- $V_{DS}$  (V) = -30V
- $I_D$  = -15 A ( $V_{GS}$  = -10V)
- $R_{DS(ON)} < 7.5\text{m}\Omega$  ( $V_{GS} = -10\text{V}$ )
- $R_{DS(ON)} < 12\text{m}\Omega$  ( $V_{GS} = -4.5\text{V}$ )

SOP-8

Unit: mm



## ■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current	$I_D$	-15	A
		-12.8	
Pulsed Drain Current	$I_{DM}$	-80	
Avalanche Current	$I_{AS}, I_{AR}$	30	
Avalanche energy	$E_{AS}, E_{AR}$	135	mJ
Power Dissipation	$P_D$	3.1	W
		2	
Thermal Resistance.Junction- to-Ambient	$R_{thJA}$	40	$^\circ\text{C}/\text{W}$
		75	
Thermal Resistance.Junction- to-Lead	$R_{thJL}$	24	$^\circ\text{C}$
Junction Temperature	$T_J$	150	
Junction Storage Temperature Range	$T_{stg}$	-55 to 150	

## ■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>DSS</sub>	I <sub>D</sub> =-250 μA, V <sub>GS</sub> =0V	-30			V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>D</sub> =-30V, V <sub>GS</sub> =0V			-5	uA
		V <sub>D</sub> =-30V, V <sub>GS</sub> =0V, T <sub>J</sub> =55°C			-25	
Gate-Body leakage current	I <sub>GSS</sub>	V <sub>D</sub> =0V, V <sub>GS</sub> =±20V			±100	nA
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>D</sub> =V <sub>GS</sub> I <sub>D</sub> =-250 μA	-1.4		-2.7	V
Static Drain-Source On-Resistance	R <sub>D(on)</sub>	V <sub>GS</sub> =-10V, I <sub>D</sub> =-15A			7.5	mΩ
		V <sub>GS</sub> =-10V, I <sub>D</sub> =-15A T <sub>J</sub> =125°C			11.5	
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-10A			12	
On state drain current	I <sub>D(on)</sub>	V <sub>GS</sub> =-10V, V <sub>D</sub> =-5V	-80			A
Forward Transconductance	g <sub>FS</sub>	V <sub>D</sub> =-5V, I <sub>D</sub> =-15A	35	50		S
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>D</sub> =-15V, f=1MHz		5270	6400	pF
Output Capacitance	C <sub>oss</sub>			945		
Reverse Transfer Capacitance	C <sub>rss</sub>			745		
Gate resistance	R <sub>g</sub>	V <sub>GS</sub> =0V, V <sub>D</sub> =0V, f=1MHz		2	3	Ω
Total Gate Charge (10V)	Q <sub>g</sub>	V <sub>GS</sub> =-10V, V <sub>D</sub> =-15V, I <sub>D</sub> =-15A		100	120	nC
Total Gate Charge (4.5V)				51.5		
Gate Source Charge	Q <sub>gs</sub>			14.5		
Gate Drain Charge	Q <sub>gd</sub>			23		
Turn-On DelayTime	t <sub>d(on)</sub>	V <sub>GS</sub> =-10V, V <sub>D</sub> =-15V, R <sub>L</sub> =1Ω, R <sub>GEN</sub> =3Ω		14		ns
Turn-On Rise Time	t <sub>r</sub>			16.5		
Turn-Off DelayTime	t <sub>d(off)</sub>			76.5		
Turn-Off Fall Time	t <sub>f</sub>			37.5		
Body Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> =-15A, d <sub>i</sub> /d <sub>t</sub> =100A/us		36.7	45	nC
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			28		
Maximum Body-Diode Continuous Current	I <sub>s</sub>				-5	A
Diode Forward Voltage	V <sub>SD</sub>	I <sub>s</sub> =-1A, V <sub>GS</sub> =0V			-1	V

Note : The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

## ■ Typical Characteristics

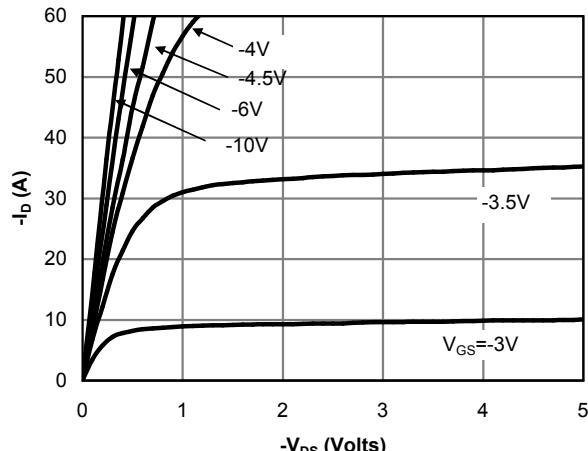


Fig 1: On-Region Characteristics (Note E)

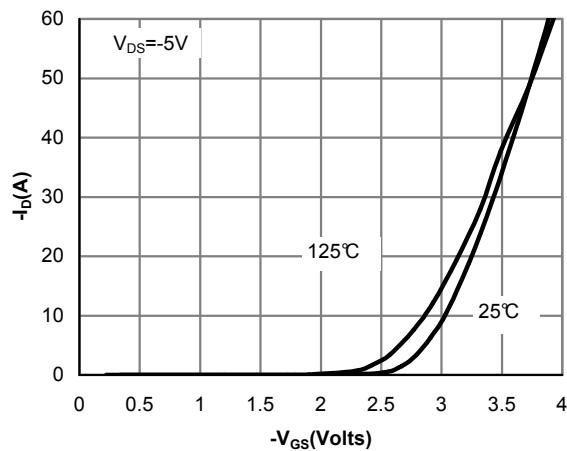


Figure 2: Transfer Characteristics (Note E)

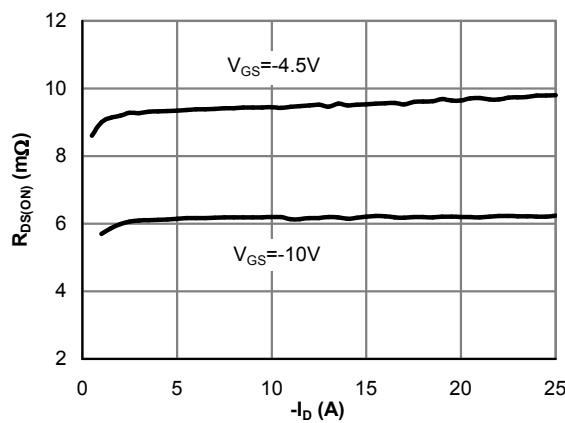


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

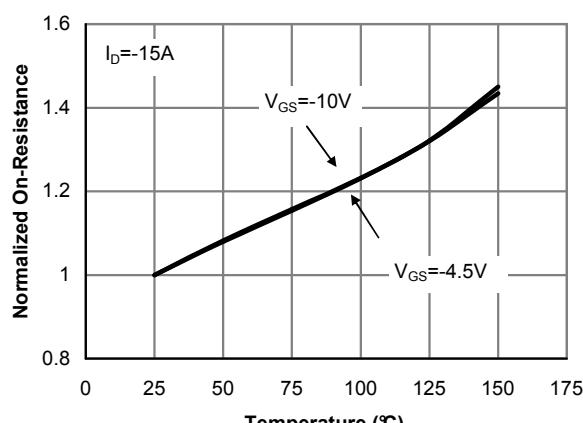


Figure 4: On-Resistance vs. Junction Temperature (Note E)

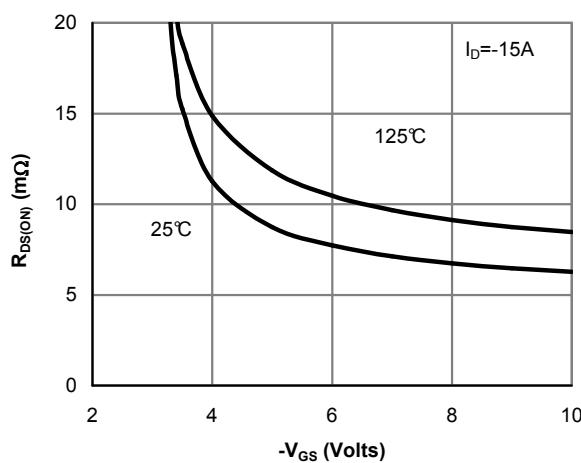


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

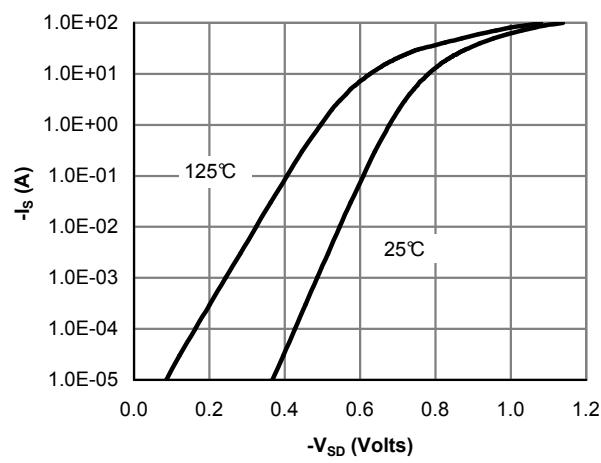


Figure 6: Body-Diode Characteristics (Note E)

## ■ Typical Characteristics

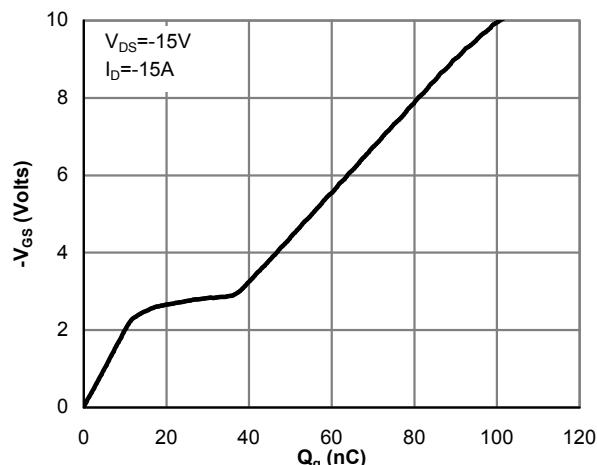


Figure 7: Gate-Charge Characteristics

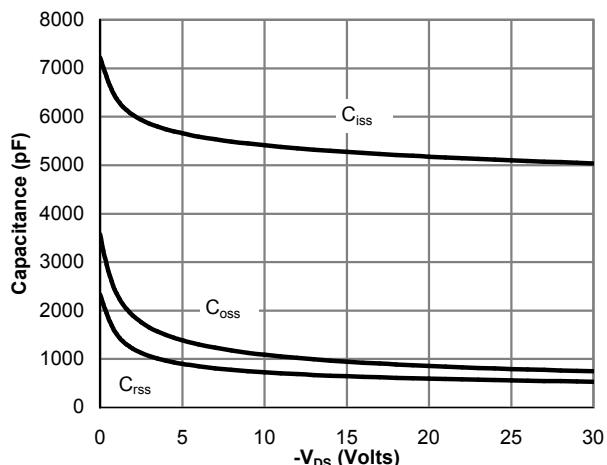


Figure 8: Capacitance Characteristics

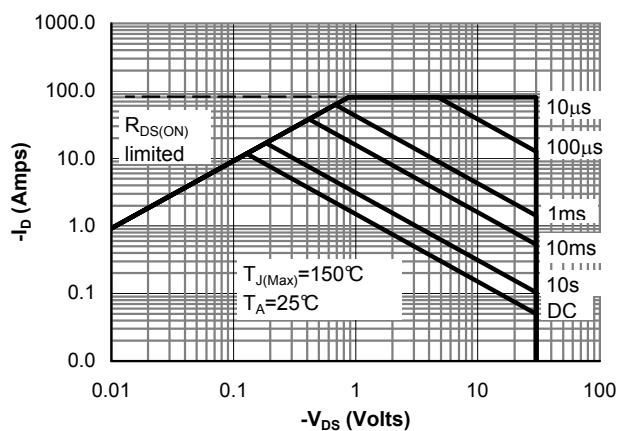


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

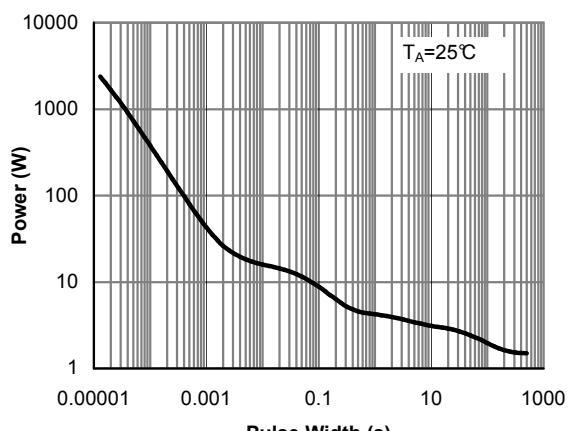


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

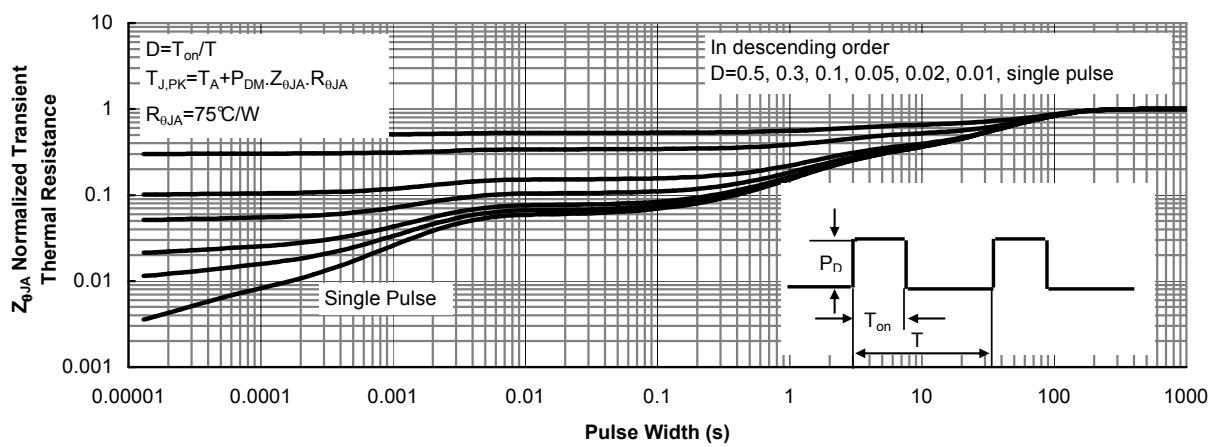


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)